

Search Notes**Application/Control No.**

10/696,775

Examiner

Stephen W. Smoot

Applicant(s)/Patent under Reexamination

FURUHASHI ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	301	5/11/2005	SWS
438	303	5/11/2005	SWS
438	675	5/11/2005	SWS
438	786	5/11/2005	SWS
438	791	5/11/2005	SWS
427	249.15	5/11/2005	SWS
427	255.27	5/11/2005	SWS
427	255.28	5/11/2005	SWS
427	255.393	5/11/2005	SWS
427	255.394	5/11/2005	SWS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words: BTBAS - Bis Tertiary Butyl Amino Silane; Hydrazine, Azido; SiN - Nitride, SiCN - Carbonitride, SiOCN;	5/11/2005	S.W.S.
Pocket Implants; Damascene Structure - Etch Stop Layer; Sacrificial Spacer.	5/12/2005	S.W.S.
Search Tools - EAST (attached); USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/11/2005	S.W.S.